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# United States Patent [19]

Yamakoshi et al.

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[45] Date of Patent: \*\*Jun. 16, 1998

[54] ANALOG MULTI-METER

D. 366,432 1/1996 Wisley et al. .... D10/78

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### [57] CLAIM

[\*\*] Term: 14 Years

The ornamental design for an analog multi-meter, as shown and described.

[21] Appl. No.: 67,663

### DESCRIPTION

[22] Filed: Mar. 6, 1997

### [30] Foreign Application Priority Data

Jan. 20, 1997 [JP] Japan ..... 9-1124

FIG. 1 is a perspective view of an analog multi-meter, with the scale omitted, showing our new design;

[51] LOC (6) Cl. .... 10-04

FIG. 2 is a front view thereof;

[52] U.S. Cl. .... D10/78

FIG. 3 is a right side view thereof;

[58] Field of Search ..... D10/78; 324/110, 324/115; 340/635, 686, 687, 693

FIG. 4 is a left side view thereof;

FIG. 5 is a rear view thereof;

FIG. 6 is a top plan view thereof; and,

FIG. 7 is a bottom view thereof.

### [56] References Cited

#### U.S. PATENT DOCUMENTS

D. 300,306 3/1989 Arnoux et al. .... D10/78

1 Claim, 4 Drawing Sheets

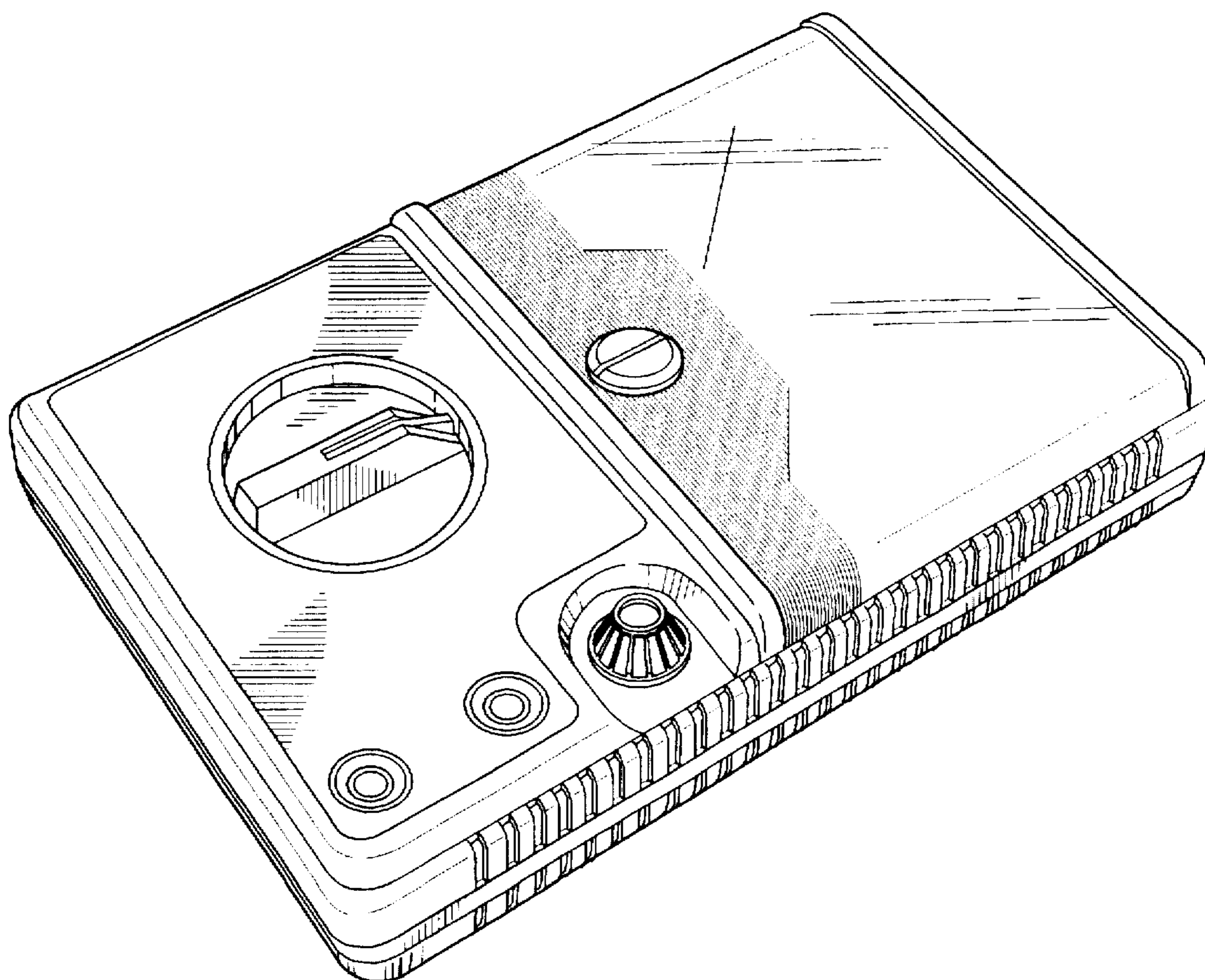


FIG. 1

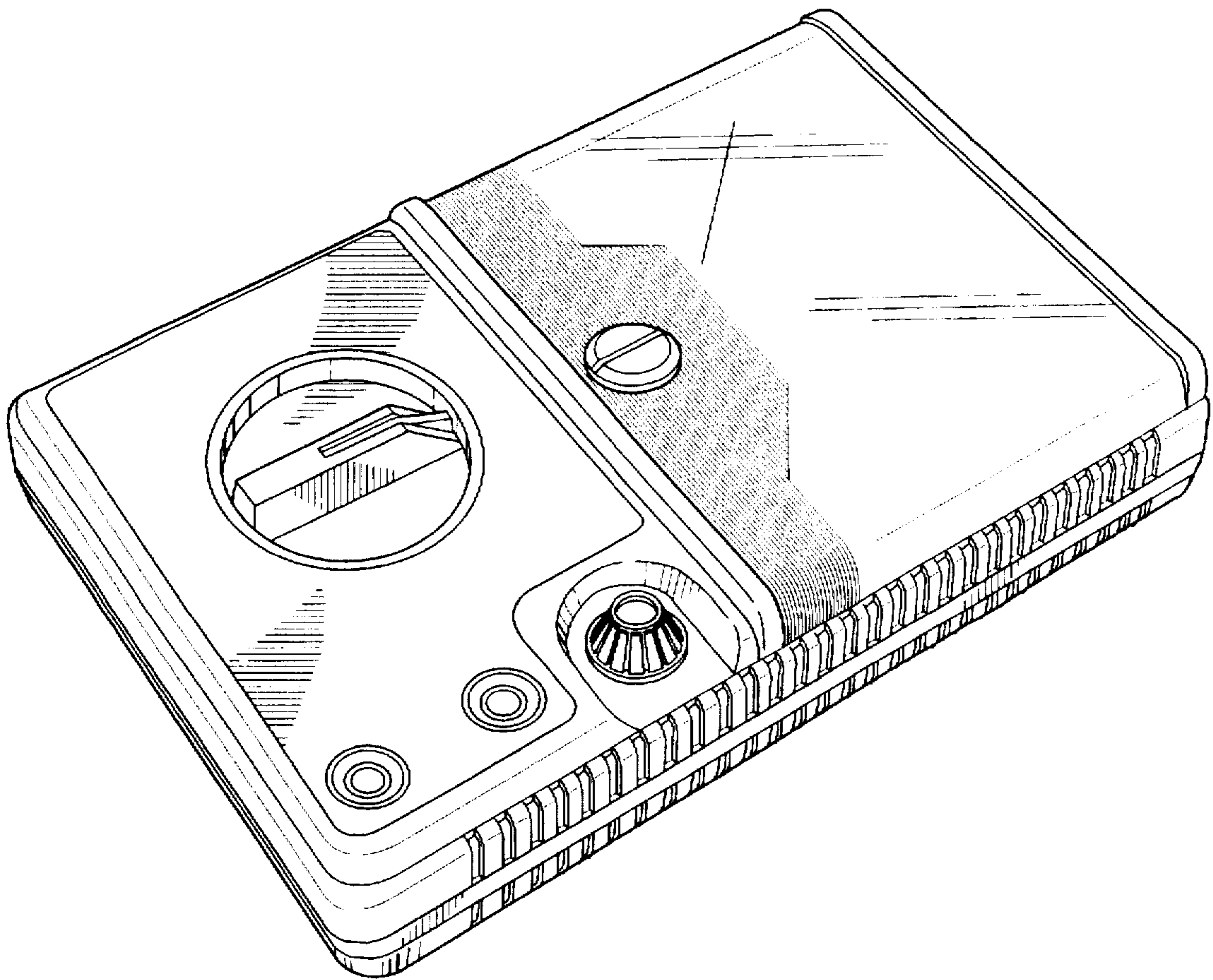


FIG. 2

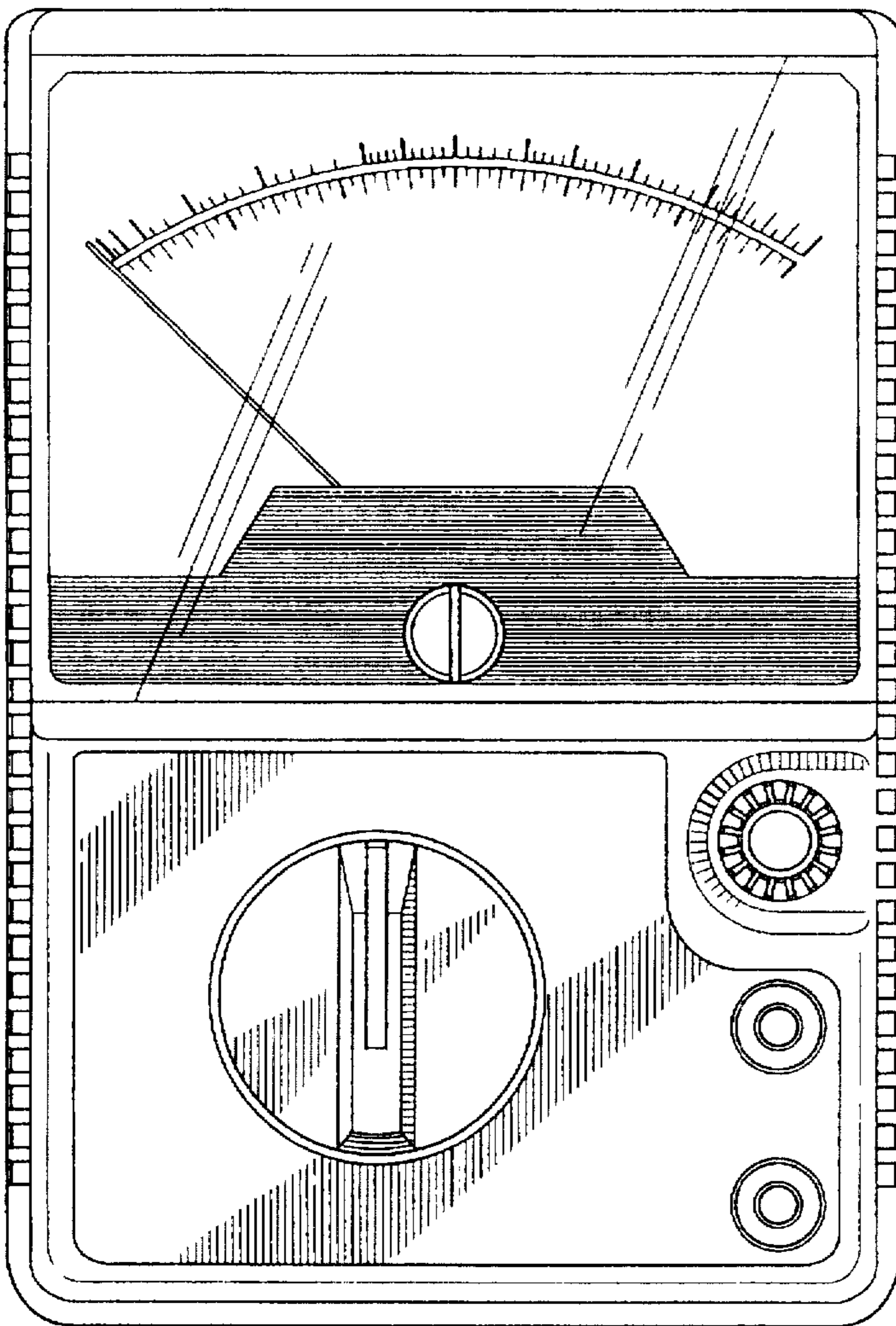


FIG. 3

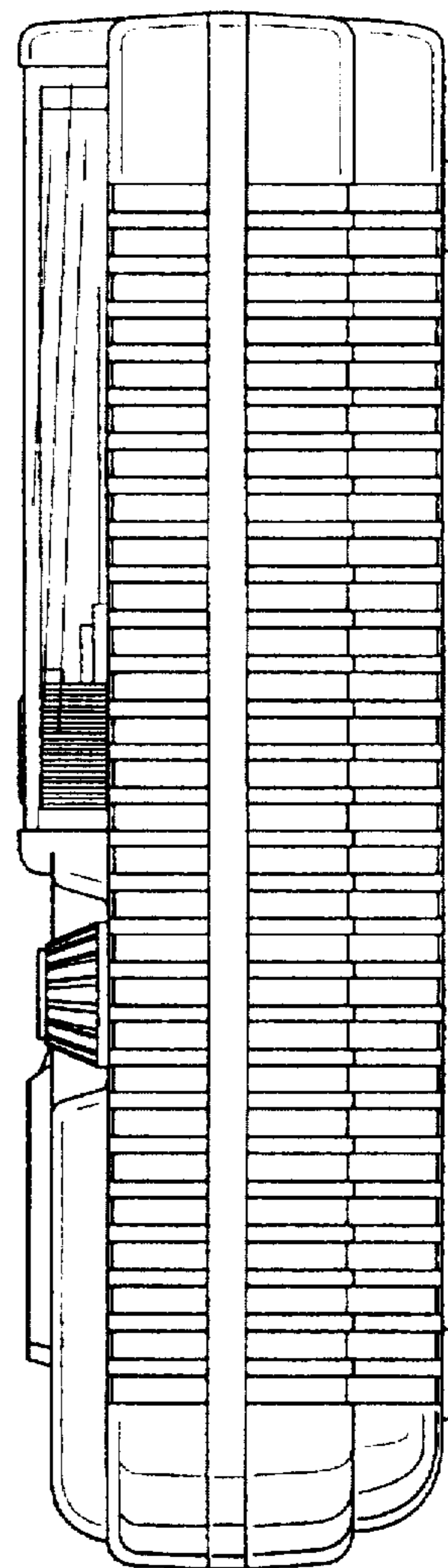




FIG. 4

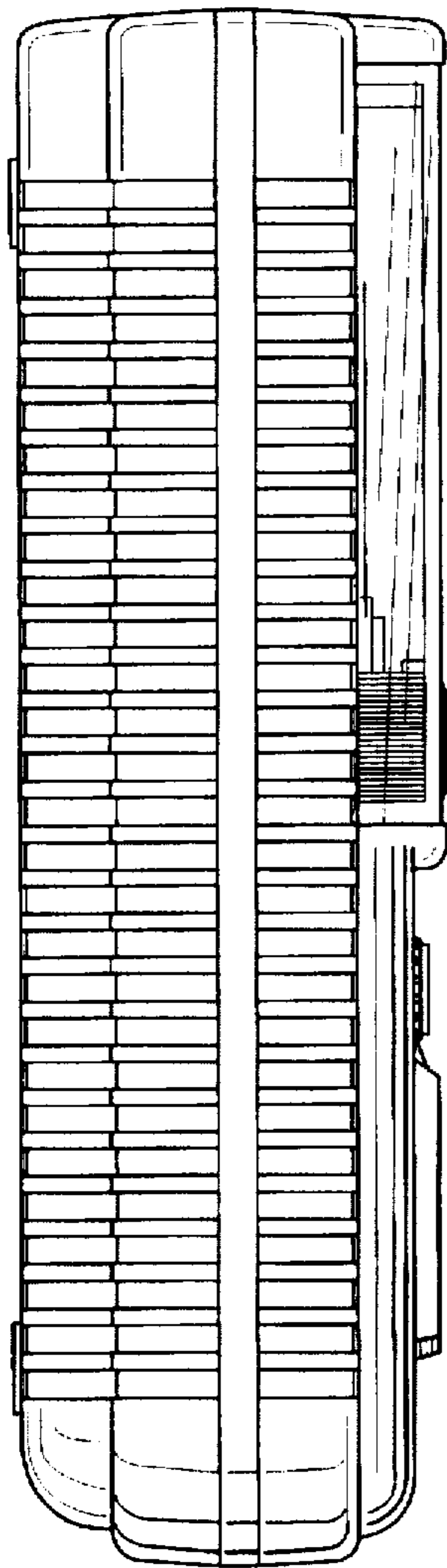


FIG. 5

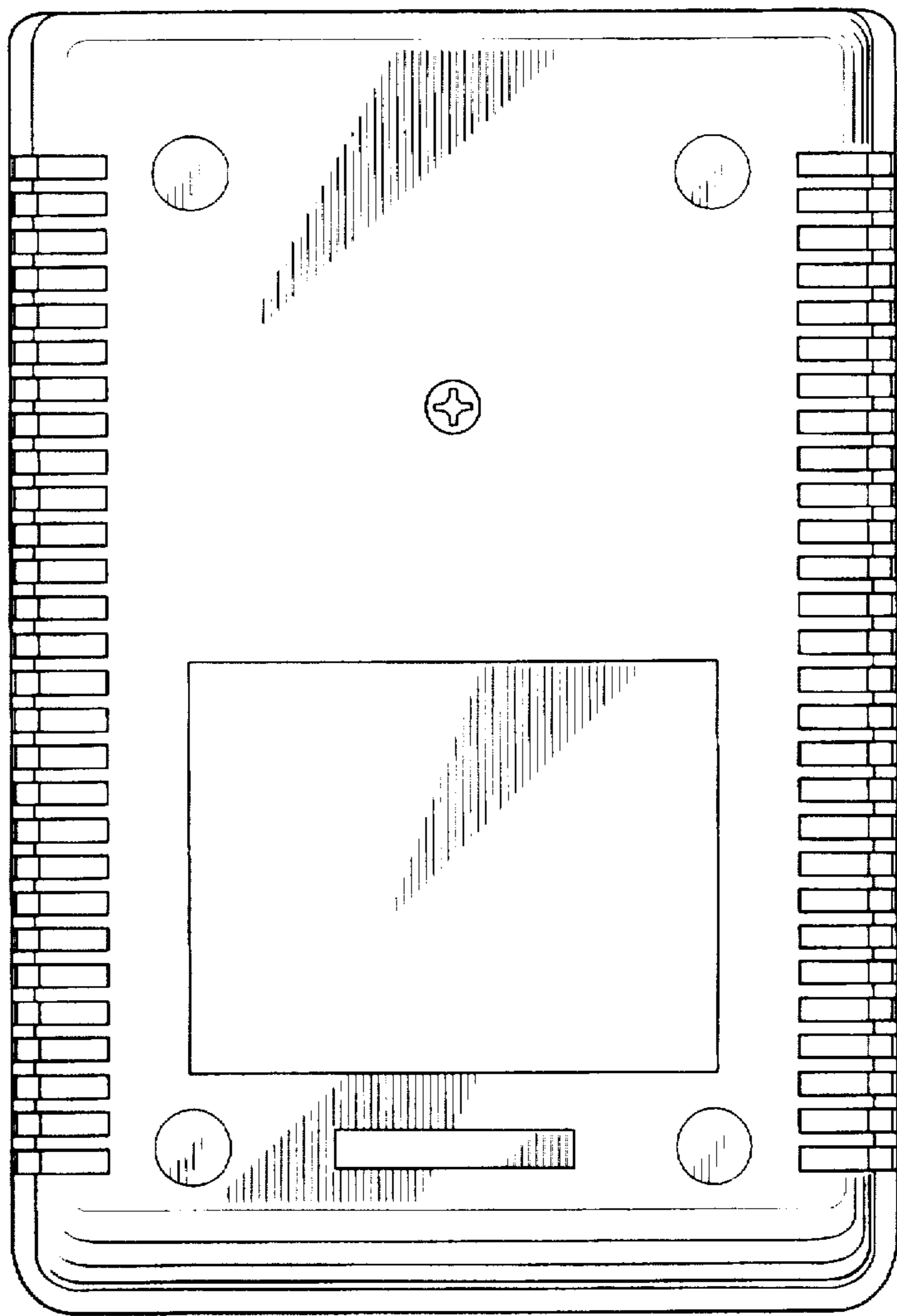


FIG. 6

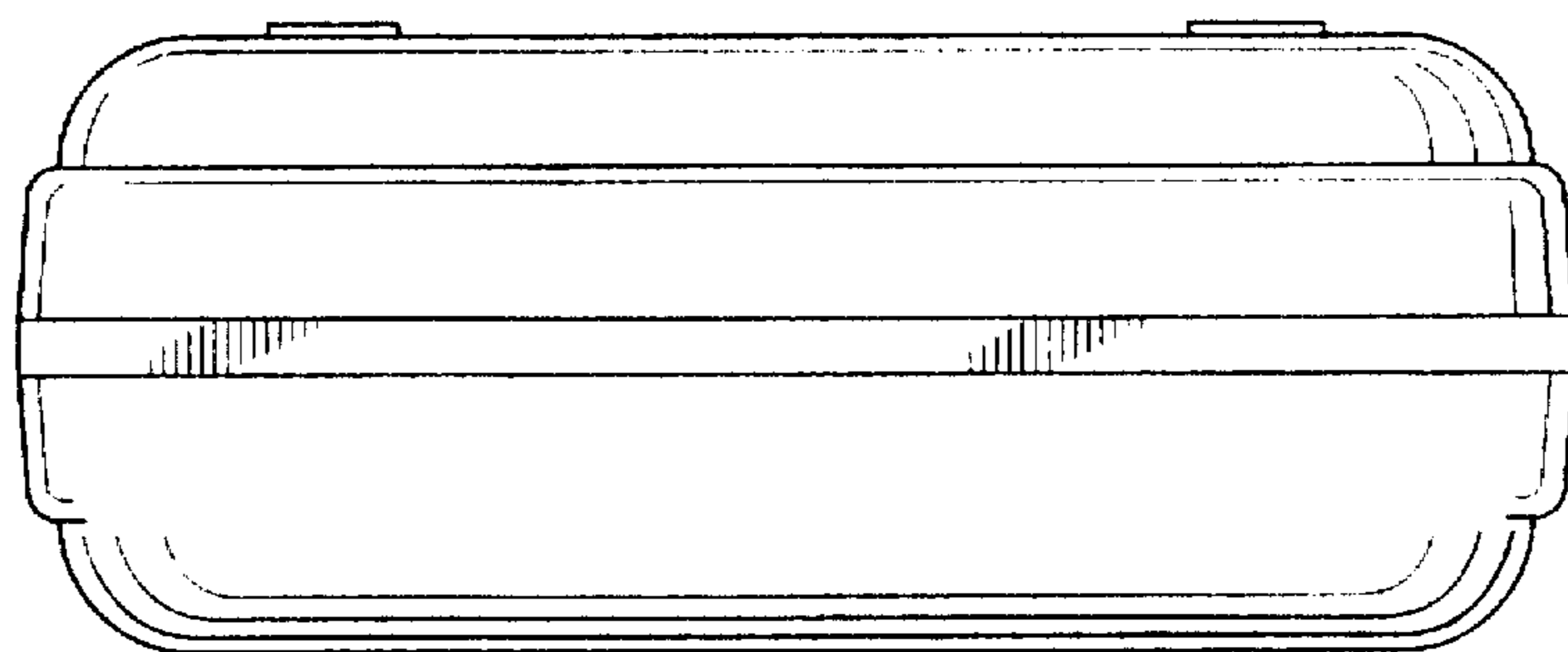


FIG. 7

